NX3008CBKS

30 / 30 V, 350 / 200 mA N/P-channel Trench MOSFET Rev. 1 — 29 July 2011 Product

Product data sheet

1. **Product profile**

1.1 General description

Complementary N/P-channel enhancement mode Field-Effect Transistor (FET) in very small SOT363 (SC-88) Surface-Mounted Device (SMD) plastic package using Trench MOSFET technology.

1.2 Features and benefits

Low threshold voltage

Very fast switching

■ Trench MOSFET technology

ESD protection up to 2 kV

AEC-Q101 qualified

1.3 Applications

Level shifter

Power supply converter

Load switch

Switching circuits

1.4 Quick reference data

Table 1. Quick reference data

| Symbol | Parameter | Conditions | | Min | Тур | Max | Unit |
|---|----------------------------------|--|-----|-----|-----|------|------|
| TR2 (P-chai | nnel) | | | | | | |
| V_{DS} | drain-source voltage | T _j = 25 °C | | - | - | -30 | V |
| V_{GS} | gate-source voltage | | | -8 | - | 8 | V |
| I_D | drain current | $V_{GS} = -4.5 \text{ V}; T_{amb} = 25 ^{\circ}\text{C}$ | [1] | - | - | -200 | mA |
| TR1 (N-chai | nnel) | | | | | | |
| V_{DS} | drain-source voltage | T _j = 25 °C | | - | - | 30 | V |
| V_{GS} | gate-source voltage | | | -8 | - | 8 | V |
| I_D | drain current | $V_{GS} = 4.5 \text{ V}; T_{amb} = 25 ^{\circ}\text{C}$ | [1] | - | - | 350 | mA |
| TR1 (N-chai | nnel), Static characteri | stics | | | | | |
| R _{DSon} | drain-source on-state resistance | $V_{GS} = 4.5 \text{ V}; I_D = 350 \text{ mA};$ $T_j = 25 \text{ °C}$ | | - | 1 | 1.4 | Ω |
| TR2 (P-channel), Static characteristics | | | | | | | |
| R _{DSon} | drain-source on-state resistance | $V_{GS} = -4.5 \text{ V};$ $I_D = -200 \text{ mA}; T_j = 25 \text{ °C}$ | | - | 2.8 | 4.1 | Ω |

^[1] Device mounted on an FR4 PCB, single-sided copper, tin-plated and mounting pad for drain 1 cm².



2. Pinning information

Table 2. Pinning information

| Pin | Symbol | Description | Simplified outline | Graphic symbol |
|-----|--------|-------------|--------------------|-----------------|
| 1 | S1 | source TR1 | O. O. O. | D4 D0 |
| 2 | G1 | gate TR1 | 654 | D1 D2 |
| 3 | D2 | drain TR2 | | |
| 4 | S2 | source TR2 | 0 | G1 $G2$ |
| 5 | G2 | gate TR2 | □1 □2 □3 | |
| 6 | D1 | drain TR1 | SOT363 (SC-88) | 14 12 |
| | | | | S1 S2 017aaa262 |

3. Ordering information

Table 3. Ordering information

| Type number | Package | | | | |
|-------------|---------|--|---------|--|--|
| | Name | Description | Version | | |
| NX3008CBKS | SC-88 | plastic surface-mounted package; 6 leads | SOT363 | | |

4. Marking

Table 4. Marking codes

| Type number | Marking code ^[1] |
|-------------|-----------------------------|
| NX3008CBKS | LD% |

^[1] % = placeholder for manufacturing site code.

5. Limiting values

Table 5. Limiting values

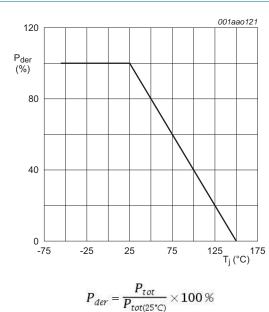
In accordance with the Absolute Maximum Rating System (IEC 60134).

| Symbol | Parameter | Conditions | Min | Max | Unit |
|------------------|---------------------------------|--|--------------|------|------|
| TR2 (P-char | nnel) | | | | |
| V_{DS} | drain-source voltage | T _j = 25 °C | - | -30 | V |
| V_{GS} | gate-source voltage | | -8 | 8 | V |
| I_D | drain current | V _{GS} = -4.5 V; T _{amb} = 25 °C | <u>[1]</u> _ | -200 | mA |
| | | V _{GS} = -4.5 V; T _{amb} = 100 °C | <u>[1]</u> _ | -125 | mA |
| I _{DM} | peak drain current | $T_{amb} = 25$ °C; single pulse; $t_p \le 10 \mu s$ | - | -0.8 | Α |
| P _{tot} | total power dissipation | T _{amb} = 25 °C | [2] | 280 | mW |
| | | | <u>[1]</u> _ | 320 | mW |
| | | T _{sp} = 25 °C | - | 990 | mW |
| TR1 (N-char | nnel) | | | | |
| V_{DS} | drain-source voltage | T _j = 25 °C | - | 30 | V |
| V_{GS} | gate-source voltage | | -8 | 8 | V |
| I_{D} | drain current | $V_{GS} = 4.5 \text{ V}; T_{amb} = 25 ^{\circ}\text{C}$ | <u>[1]</u> _ | 350 | mA |
| | | $V_{GS} = 4.5 \text{ V}; T_{amb} = 100 ^{\circ}\text{C}$ | <u>[1]</u> _ | 230 | mA |
| I_{DM} | peak drain current | T_{amb} = 25 °C; single pulse; $t_p \le 10 \mu s$ | - | 1.4 | Α |
| P _{tot} | total power dissipation | T _{amb} = 25 °C | [2] | 280 | mW |
| | | | <u>[1]</u> _ | 320 | mW |
| | | T _{sp} = 25 °C | - | 990 | mW |
| Per device | | | | | |
| P _{tot} | total power dissipation | T _{amb} = 25 °C | [2] | 445 | mW |
| T_j | junction temperature | | -55 | 150 | °C |
| T_{amb} | ambient temperature | | -55 | 150 | °C |
| T_{stg} | storage temperature | | -65 | 150 | °C |
| TR1 (N-char | nnel), Source-drain diode | | | | |
| I _S | source current | T _{amb} = 25 °C | <u>[1]</u> - | 300 | mA |
| TR2 (P-char | nnel), Source-drain diode | | | | |
| Is | source current | T _{amb} = 25 °C | <u>[1]</u> - | -200 | mA |
| TR1 N-chan | nel), ESD maximum rating | | | | |
| V_{ESD} | electrostatic discharge voltage | НВМ | <u>[3]</u> _ | 2000 | V |
| TR2 (P-char | nnel), ESD maximum rating | | | | |
| V _{ESD} | electrostatic discharge voltage | НВМ | <u>[3]</u> _ | 2000 | V |
| | | | | | |

 $[\]label{eq:condition} \textbf{[1]} \quad \text{Device mounted on an FR4 PCB, single-sided copper, tin-plated and mounting pad for drain 1 cm2.}$

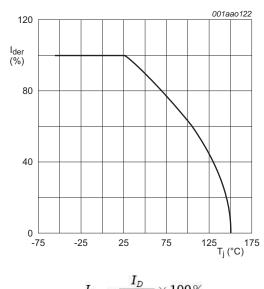
^[2] Device mounted on an FR4 Printed-Circuit Board (PCB), single-sided copper; tin-plated and standard footprint.

^[3] Measured between all pins.



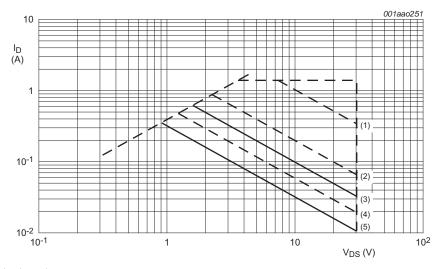
Normalized total power dissipation as a

function of junction temperature



 $I_{der} = \frac{I_D}{I_{D(25^{\circ}C)}} \times 100\%$

Fig 2. Normalized continuous drain current as a function of junction temperature



I_{DM} is a single pulse

(1)
$$t_p = 1 \text{ ms}$$

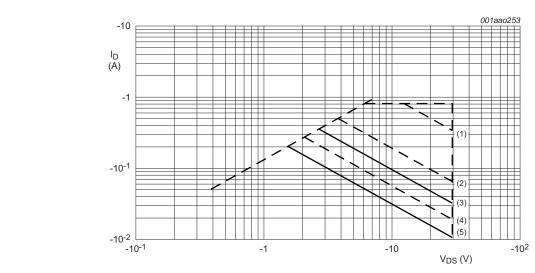
(2)
$$t_p = 10 \text{ ms}$$

(3) DC;
$$T_{sp} = 25 \, ^{\circ}\text{C}$$

(4)
$$t_p = 100 \text{ ms}$$

(5) DC; T_{amb} = 25 °C; 1 cm² drain mounting pad

Safe operating area TR1 (N-channel); junction to ambient; continuous and peak drain currents as a Fig 3. function of drain-source voltage



I_{DM} is a single pulse

(1) $t_p = 1 \text{ ms}$

NXP Semiconductors

- (2) $t_p = 10 \text{ ms}$
- (3) DC; $T_{sp} = 25 \, ^{\circ}\text{C}$
- (4) $t_p = 100 \text{ ms}$
- (5) DC; T_{amb} = 25 °C; 1 cm² drain mounting pad

Fig 4. Safe operating area TR2 (P-channel); junction to ambient; continuous and peak drain currents as a function of drain-source

6. Thermal characteristics

Table 6. Thermal characteristics

| Symbol | Parameter | Conditions | | Min | Тур | Max | Unit |
|-----------------------|--|-------------|------------|-----|-----|-----|------|
| Per device | | | | | | | |
| R _{th(j-a)} | thermal resistance from junction to ambient | in free air | [1] | - | - | 300 | K/W |
| TR1 (N-chann | el) | | | | | | |
| R _{th(j-a)} | thermal resistance from junction to ambient | in free air | [1] | - | 390 | 445 | K/W |
| | | | [2] | - | 340 | 390 | K/W |
| R _{th(j-sp)} | thermal resistance from junction to solder point | | | - | - | 130 | K/W |
| TR2 (P-chann | el) | | | | | | |
| R _{th(j-a)} | thermal resistance from junction to ambient | in free air | <u>[1]</u> | - | 390 | 445 | K/W |
| | | | [2] | - | 340 | 390 | K/W |
| R _{th(j-sp)} | thermal resistance from junction to solder point | | | - | - | 130 | K/W |

^[1] Device mounted on an FR4 Printed-Circuit Board (PCB), single-sided copper; tin-plated and standard footprint.

^[2] Device mounted on an FR4 PCB, single-sided copper, tin-plated and mounting pad for drain 1 cm².

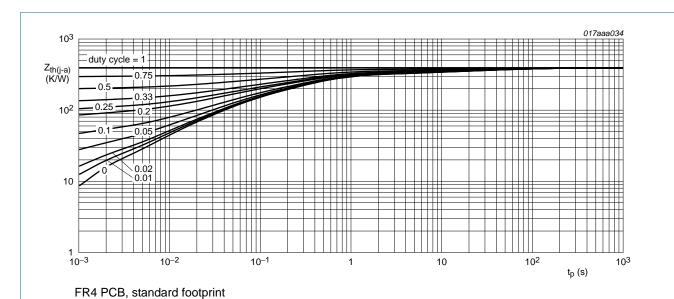
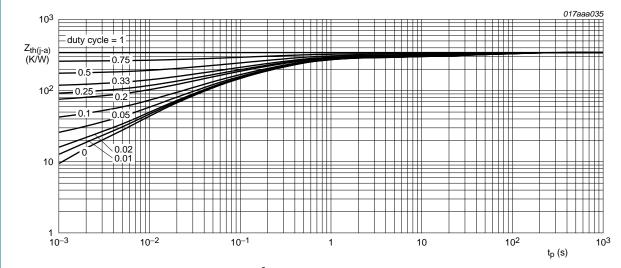
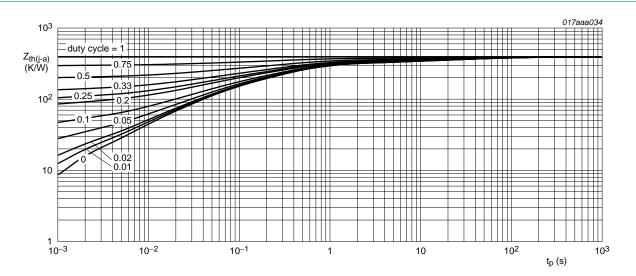


Fig 5. TR1: Transient thermal impedance from junction to ambient as a function of pulse duration; typical values



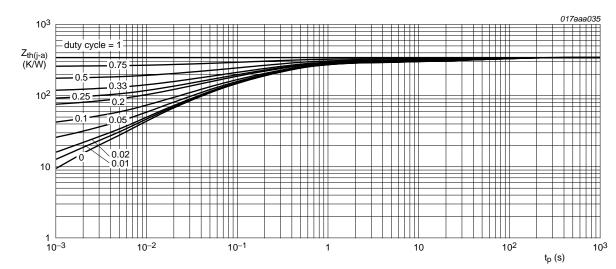
FR4 PCB, mounting pad for drain 1 cm².

Fig 6. TR1: Transient thermal impedance from junction to ambient as a function of pulse duration; typical values



FR4 PCB, standard footprint

Fig 7. TR2, Transient thermal impedance from junction to ambient as a function of pulse duration; typical values



FR4 PCB, mounting pad for drain 1 cm²

Fig 8. TR2, Transient thermal impedance from junction to ambient as a function of pulse duration; typical values

7. Characteristics

Table 7. Characteristics

| Symbol | Parameter | Conditions | Min | Тур | Max | Unit |
|---------------------|-----------------------------------|--|------|------|------|------|
| TR2 (P-cha | nnel), Static characteristic | s | | | | |
| $V_{(BR)DSS}$ | drain-source breakdown voltage | $I_D = -250 \ \mu A; \ V_{GS} = 0 \ V; \ T_j = 25 \ ^{\circ}C$ | -30 | - | - | V |
| V_{GSth} | gate-source threshold voltage | $I_D = -250 \mu A; V_{DS} = V_{GS}; T_j = 25 \text{ °C}$ | -0.6 | -0.9 | -1.1 | V |
| I_{DSS} | drain leakage current | $V_{DS} = -30 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$ | - | - | -1 | μΑ |
| | | $V_{DS} = -30 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 150 \text{ °C}$ | - | - | -10 | μΑ |
| I_{GSS} | gate leakage current | $V_{GS} = 8 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$ | - | -0.2 | -1 | μΑ |
| | | $V_{GS} = -8 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$ | - | -0.2 | -1 | μΑ |
| | | $V_{GS} = 4.5 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$ | - | -10 | - | nΑ |
| | | V_{GS} = -4.5 V; V_{DS} = 0 V; T_j = 25 °C | - | -10 | - | nΑ |
| | | $V_{GS} = 2.5 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$ | - | -1 | - | nΑ |
| | | $V_{GS} = -2.5 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$ | - | -1 | - | nΑ |
| R _{DSon} | drain-source on-state | V_{GS} = -4.5 V; I_D = -200 mA; T_j = 25 °C | - | 2.8 | 4.1 | Ω |
| | resistance | $V_{GS} = -2.5 \text{ V}; I_D = -10 \text{ mA}; T_j = 25 \text{ °C}$ | - | 5.3 | 6.5 | Ω |
| | | $V_{GS} = -4.5 \text{ V}; I_D = -200 \text{ mA}; T_j = 150 ^{\circ}\text{C}$ | - | 5.3 | 7.8 | Ω |
| g _{fs} | transfer conductance | $V_{DS} = -10 \text{ V}; I_D = -200 \text{ mA}; T_j = 25 \text{ °C}$ | - | 160 | - | mS |
| TR1 (N-cha | nnel), Static characteristic | s | | | | |
| $V_{(BR)DSS}$ | drain-source breakdown voltage | $I_D = 250 \mu A; V_{GS} = 0 V; T_j = 25 °C$ | 30 | - | - | V |
| V_{GSth} | gate-source threshold voltage | $I_D = 250 \mu A; V_{DS} = V_{GS}; T_j = 25 \text{ °C}$ | 0.6 | 0.9 | 1.1 | V |
| I _{DSS} | drain leakage current | $V_{DS} = 30 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$ | - | - | 1 | μΑ |
| | | $V_{DS} = 30 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 150 ^{\circ}\text{C}$ | - | - | 10 | μΑ |
| I _{GSS} | gate leakage current | $V_{GS} = 8 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$ | - | 0.2 | 1 | μΑ |
| | | $V_{GS} = -8 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$ | - | 0.2 | 1 | μΑ |
| | | $V_{GS} = 4.5 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$ | - | 10 | - | nA |
| | | $V_{GS} = -4.5 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$ | - | 10 | - | nA |
| | | $V_{GS} = 2.5 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$ | - | 1 | - | nA |
| | | $V_{GS} = -2.5 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$ | - | 1 | - | nA |
| R _{DSon} | drain-source on-state | $V_{GS} = 4.5 \text{ V}; I_D = 350 \text{ mA}; T_j = 25 \text{ °C}$ | - | 1 | 1.4 | Ω |
| | resistance | $V_{GS} = 4.5 \text{ V}; I_D = 350 \text{ mA}; T_j = 150 \text{ °C}$ | - | 1.8 | 2.5 | Ω |
| | | $V_{GS} = 2.5 \text{ V}; I_D = 200 \text{ mA}; T_j = 25 \text{ °C}$ | - | 1.4 | 2.1 | Ω |
| | | $V_{GS} = 1.8 \text{ V}; I_D = 10 \text{ mA}; T_j = 25 \text{ °C}$ | - | 2 | 2.8 | Ω |
| 9 _{fs} | transfer conductance | $V_{DS} = 10 \text{ V}; I_D = 350 \text{ mA}; T_j = 25 \text{ °C}$ | - | 310 | - | mS |
| TR1 (N-cha | nnel), Dynamic characteri | stics | | | | |
| Q _{G(tot)} | total gate charge | $V_{DS} = 15 \text{ V}; I_D = 350 \text{ mA}; V_{GS} = 4.5 \text{ V};$ | - | 0.52 | 0.68 | nC |
| Q _{GS} | gate-source charge | T _j = 25 °C | - | 0.17 | - | nC |
| | | | | | | |

Table 7. Characteristics ... continued

| Symbol | Parameter | Conditions | Min | Тур | Max | Unit |
|---------------------|------------------------------|--|-------|-------|------|------|
| C _{iss} | input capacitance | $V_{DS} = 15 \text{ V}; f = 1 \text{ MHz}; V_{GS} = 0 \text{ V};$ | - | 34 | 50 | pF |
| Coss | output capacitance | T _j = 25 °C | - | 6.5 | - | pF |
| C _{rss} | reverse transfer capacitance | | - | 2.2 | - | pF |
| t _{d(on)} | turn-on delay time | $V_{DS} = 20 \text{ V}; R_L = 250 \Omega; V_{GS} = 4.5 \text{ V};$ | - | 15 | 30 | ns |
| t _r | rise time | $R_{G(ext)} = 6 \Omega; T_j = 25 °C$ | - | 11 | - | ns |
| t _{d(off)} | turn-off delay time | | - | 69 | 138 | ns |
| t _f | fall time | | - | 19 | - | ns |
| TR2 (P-chani | nel), Dynamic characteri | istics | | | | |
| Q _{G(tot)} | total gate charge | $V_{DS} = -15 \text{ V; } I_D = -200 \text{ mA;}$ $V_{GS} = -4.5 \text{ V; } T_j = 25 \text{ °C}$ | - | 0.55 | 0.72 | nC |
| Q_{GS} | gate-source charge | | - | 0.23 | - | nC |
| Q_{GD} | gate-drain charge | | - | 0.09 | - | nC |
| C _{iss} | input capacitance | $V_{DS} = -15 \text{ V}; f = 1 \text{ MHz}; V_{GS} = 0 \text{ V};$ | - | 31 | 46 | pF |
| C _{oss} | output capacitance | T _j = 25 °C | - | 6.5 | - | pF |
| C _{rss} | reverse transfer capacitance | | - | 2.3 | - | pF |
| t _{d(on)} | turn-on delay time | V_{DS} = -20 V; R_L = 250 Ω ; V_{GS} = -4.5 V; | - | 19 | 38 | ns |
| t _r | rise time | $R_{G(ext)} = 6 \Omega; T_j = 25 °C$ | - | 30 | - | ns |
| t _{d(off)} | turn-off delay time | | - | 65 | 130 | ns |
| t _f | fall time | | - | 38 | - | ns |
| TR2 (P-chann | nel), Source-drain diode | characteristics | | | | |
| V_{SD} | source-drain voltage | $I_S = -200 \text{ mA}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$ | -0.47 | -0.88 | -1.2 | V |
| TD4 /N chan | nel), Source-drain diode | characteristics | | | | |
| TRT (N-Chan | nei), oodi ce-arain diode | | | | | |

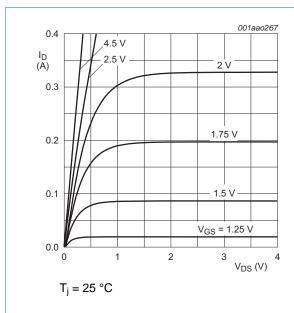
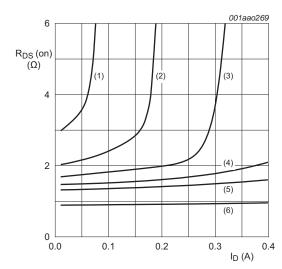


Fig 9. TR1: Output characteristics: drain current as a function of drain-source voltage; typical values



T_i = 25 °C

(1) $V_{GS} = 1.5 \text{ V}$

(2) $V_{GS} = 1.75 \text{ V}$

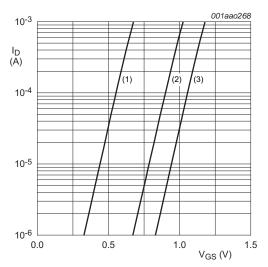
(3) $V_{GS} = 2.0 \text{ V}$

(4) $V_{GS} = 2.25 \text{ V}$

(5) $V_{GS} = 2.5 \text{ V}$

(6) $V_{GS} = 4.5 \text{ V}$

Fig 11. TR1: Drain-source on-state resistance as a function of drain current; typical values



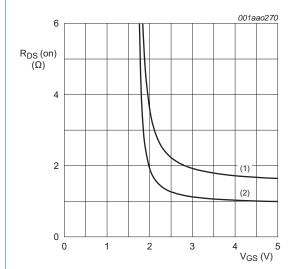
 $T_{j} = 25 \, ^{\circ}C; \, V_{DS} = 5 \, V$

(1) minimum values

(2) typical values

(3) maximum values

Fig 10. TR1: Sub-threshold drain current as a function of gate-source voltage

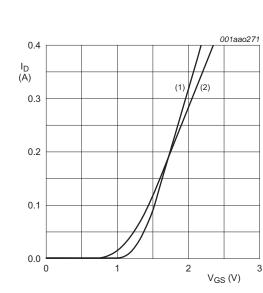


 $I_D = 350 \text{ mA}$

(1) $T_i = 150 \, ^{\circ}C$

(2) $T_i = 25 \, ^{\circ}\text{C}$

Fig 12. TR1: Drain-source on-state resistance as a function of gate-source voltage; typical values



 $V_{DS} > I_D \times R_{DSon}$

(1)
$$T_j = 25 \, ^{\circ}C$$

(2)
$$T_i = 150 \, ^{\circ}\text{C}$$

Fig 13. TR1: Transfer characteristics: drain current as a function of gate-source voltage; typical values

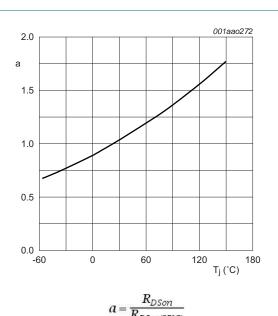
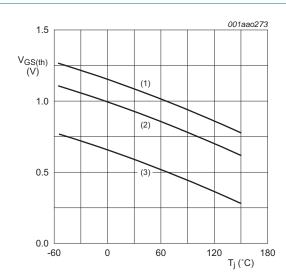


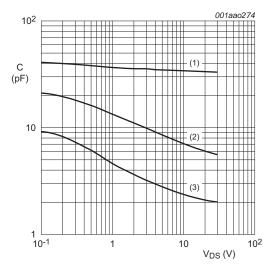
Fig 14. TR1: Normalized drain-source on-state resistance as a function of junction temperature; typical values



 $I_D = 0.25 \text{ mA}; V_{DS} = V_{GS}$

- (1) maximum values
- (2) typical values
- (3) minimum values

Fig 15. TR1: Gate-source threshold voltage as a function of junction temperature



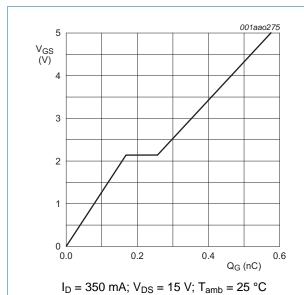
 $f = 1 \text{ MHz}; V_{GS} = 0 \text{ V}$

(1)C_{iss}

(2)Coss

(3)C_{rss}

Fig 16. TR1: Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values



V_{DS}

V_{GS(pl)}

V_{GS(th)}

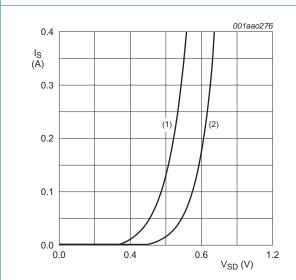
Q_{GS1} Q_{GS2}

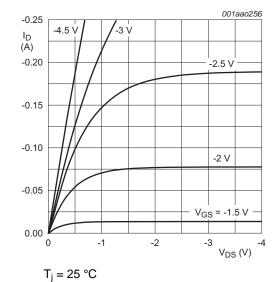
Q_{GS} Q_{G(tot)}

003aaa508

Fig 17. TR1: Gate-source voltage as a function of gate charge; typical values

Fig 18. Gate charge waveform definitions

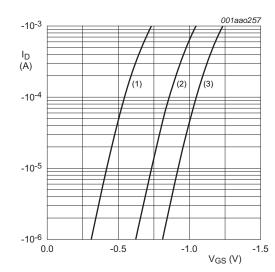




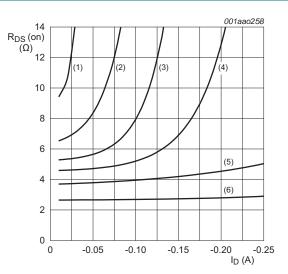
 $V_{GS} = 0 V$ (1) $T_j = 150 \,^{\circ}C$ (2) $T_j = 25 \,^{\circ}C$

Fig 19. TR1: Source current as a function of source-drain voltage; typical values

Fig 20. TR2: Output characteristics: drain current as a function of drain-source voltage; typical values



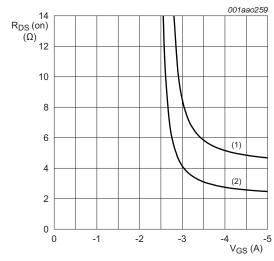
- $T_i = 25 \, ^{\circ}C; \, V_{DS} = -5 \, V$
- (1) minimum values
- (2) typical values
- (3) maximum values



- T_j = 25 °C
- (1) $V_{GS} = -1.75 \text{ V}$
- (2) $V_{GS} = -2.0 \text{ V}$
- (3) $V_{GS} = -2.25 \text{ V}$
- (4) $V_{GS} = -2.5 \text{ V}$
- (5) $V_{GS} = -3.0 \text{ V}$
- (6) $V_{GS} = -4.5 \text{ V}$

Fig 21. TR2: Sub-threshold drain current as a function of gate-source voltage



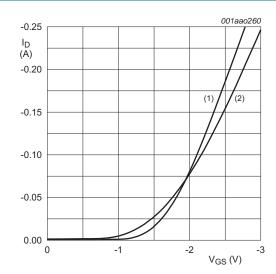


 $I_D = -200 \text{ mA}$

(1) $T_i = 150 \, ^{\circ}C$

(2) $T_i = 25 \, ^{\circ}C$

Fig 23. TR2: Drain-source on-state resistance as a function of gate-source voltage; typical values



 $V_{DS} > I_D \times R_{DSon}$

(1) $T_i = 25 \, ^{\circ}C$

(2) $T_i = 150 \, ^{\circ}\text{C}$

Fig 24. TR2: Transfer characteristics: drain current as a function of gate-source voltage; typical values

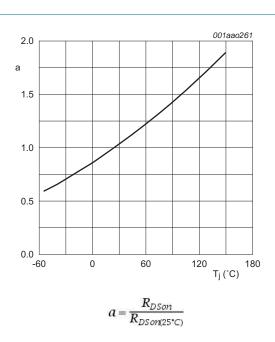
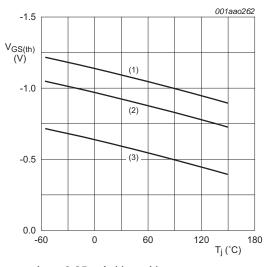


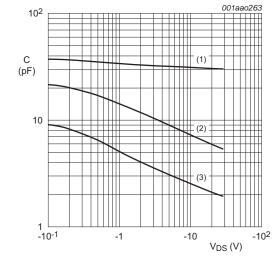
Fig 25. TR2: Normalized drain-source on-state resistance as a function of junction temperature; typical values



 I_D = -0.25 mA; V_{DS} = V_{GS}

- (1) maximum values
- (2) typical values
- (3) minimum values

Fig 26. TR2: Gate-source threshold voltage as a function of junction temperature



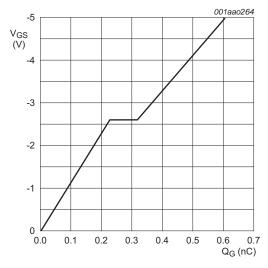
 $f = 1 \text{ MHz}; V_{GS} = 0 \text{ V}$

 $(1)C_{iss}$

(2)Coss

 $(3)C_{rss}$

Fig 27. TR2: Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values

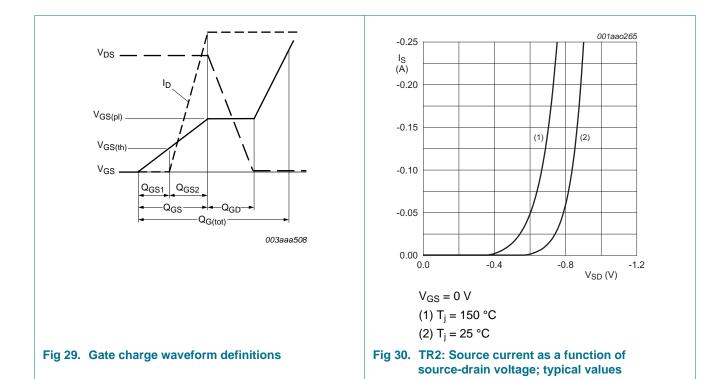


 $I_D = -200 \text{ mA}; V_{DS} = -15 \text{ V}; T_{amb} = 25 \text{ °C}$

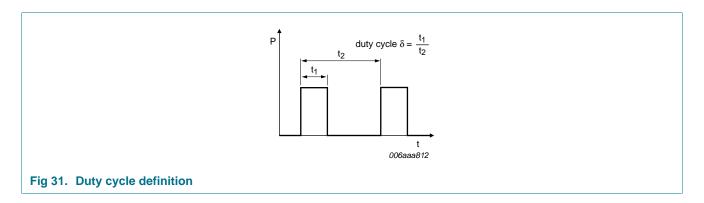
Fig 28. Gate-source voltage as a function of gate charge; typical values

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8. Test information



8.1 Quality information

This product has been qualified in accordance with the Automotive Electronics Council (AEC) standard *Q101 - Stress test qualification for discrete semiconductors*, and is suitable for use in automotive applications.

9. Package outline

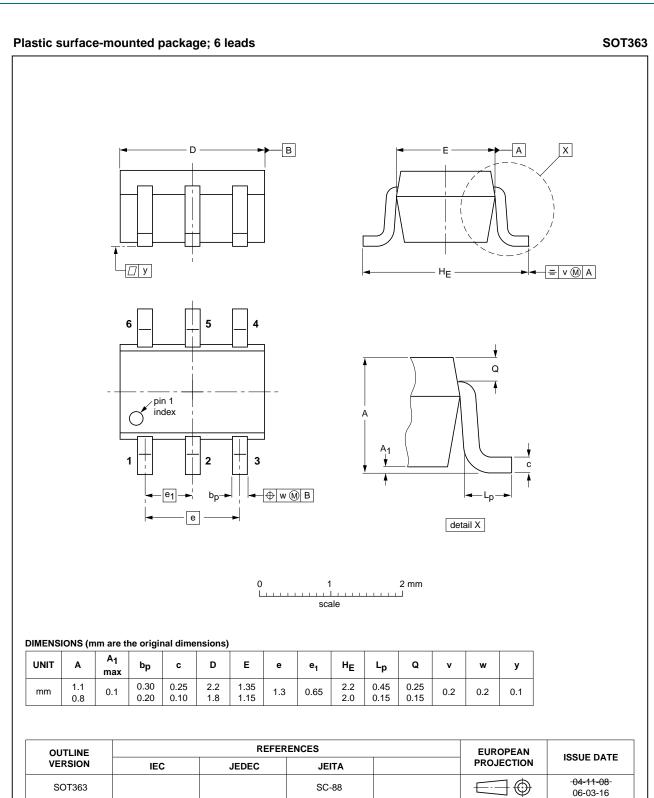


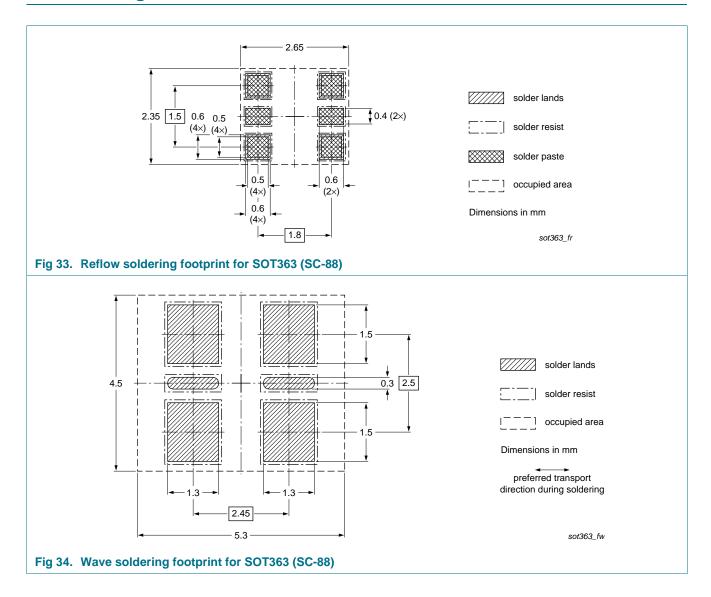
Fig 32. Package outline SOT363 (SC-88)

NX3008CBKS

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10. Soldering



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11. Revision history

Table 8. Revision history

| Document ID | Release date | Data sheet status | Change notice | Supersedes |
|----------------|--------------|--------------------|---------------|------------|
| NX3008CBKS v.1 | 20110729 | Product data sheet | - | - |

12. Legal information

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|--------------------------------|--------------------|---|
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| Preliminary [short] data sheet | Qualification | This document contains data from the preliminary specification. |
| Product [short] data sheet | Production | This document contains the product specification. |

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
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